Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination		
10/623,026	LEE ET AL.		
Examiner	Art Unit		
Tuan V. Thai	2186		

SEARCHED					
Class	Subclass	Date	Examiner		
711	5	10/21/2005	тн		
711	100	10/21/2005	тн		
711	154	10/21/2005	тн		
711	170	10/21/2005	тн		
711	200	10/21/2005	тн		
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
	1			
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
IEEE search; NPL search; EAST searches: IBMTDB DERWENTs EPO/JPO abstract USPGPUB	10/21/2005	тн
NORHT database		